





Logic Probe

parameter	Model	SPL2016	SPL1016	SPL1008
				
Input Channels		16	16	8
Input Impedance		100kΩ 18pF	100kΩ 8pF	100kΩ 18pF
Maximum Input Voltage		±50V Peak	±20V Peak	±40V Peak
Input Dynamic Range		±20V	±10V	±20V
User defined threshold range		-10V~10V (10mV steps)	-8V~8V (10mV steps)	-3V~3V (10mV steps)
Threshold Selections		TTL(1.5V), CMOS(2.5V), 3.3V_LVCMOS(1.65V), 2.5V_LVCMOS(1.25V)	TTL(1.5V), CMOS(2.5V), 3.3V_LVCMOS(1.65V), 2.5V_LVCMOS(1.25V)	TTL(1.5V), CMOS(2.5V), 3.3V_LVCMOS(1.65V), 2.5V_LVCMOS(1.25V)
Threshold Accurac		±(3% of threshold setting +200mV)	±(3% of threshold setting +150mV)	±(3% of threshold setting +400mV)
Threshold Groupings		Group 2: D15-D8 Group 1: D7-D0	Group 2: D15-D8 Group 1: D7-D0	D7-D0
Minimum Input Voltage Swing		800mVpp	800mVpp	800mVpp
Maximum Input Data Rate		300 Mbps	120 Mbps	120Mbps
Minimum Detectable Pulse Width		3.3ns	8.3ns	8.3ns
Channel-to-Channel Skew		± (1 digital sample interval)	± (1 digital sample interval)	± (1 digital sample interval)

Near Field Probe

Parameter	Model	SRF5030T-H20	SRF5030T-H10	SRF5030T-H5	SRF5030T-E5
					
Frequency Range		300kHz to 3GHz	300kHz to 3GHz	300kHz to 3GHz	300kHz to 3GHz
Resolution		20 mm	10 mm	5 mm	5 mm
Application		Radiated EMC measurement RF immunity testing Contactless (load free) relative measurement of RF signal chains Contactless (load free) relative measurement of oscillators, modulators, etc.			